

MOS INTEGRATED CIRCUIT
MC-451AB64S**1M-WORD BY 64-BIT
SYNCHRONOUS DYNAMIC RAM MODULE (SO DIMM)****Description**

The MC-451AB64S is a 1,048,576 words by 64 bits synchronous dynamic RAM module (Small Outline DIMM) on which 4 pieces of 16 M SDRAM: μPD4516161 are assembled.

This module provides high density and large quantities of memory in a small space without utilizing the surface-mounting technology on the printed circuit board.

Decoupling capacitors are mounted on power supply line for noise reduction.

Features

- 1,048,576 words by 64 bits organization
- Clock frequency and Clock access time

★	Family	/CAS latency	Clock frequency (MAX.)	Clock access time (MAX.)	Power consumption (MAX.)	
					Active	Standby
★	MC-451AB64S-A10	CL = 3	100 MHz	8 ns	2,448 mW	28.8 mW (CMOS level input)
		CL = 2	67 MHz	10 ns		
★	MC-451AB64S-A67	CL = 3	67 MHz	9 ns	2,160 mW	
		CL = 2		10 ns		
★	MC-451AB64S-A12	CL = 3	83 MHz	9 ns	2,160 mW	
		CL = 2	55 MHz	12 ns		

- Fully Synchronous Dynamic RAM, with all signals referenced to a positive clock edge
- Pulsed interface
- Possible to assert random column address in every cycle
- Dual internal banks controlled by BA0 (Bank Select)
- Programmable burst-length (1, 2, 4, 8 and Full Page)
- Programmable wrap sequence (Sequential / Interleave)
- Programmable /CAS latency (2, 3)
- Automatic precharge and controlled precharge
- CBR (Auto) refresh and self refresh
- Single 3.3 V ±0.3 V power supply
- LVTTL compatible
- 2,048 refresh cycles/32 ms
- Burst termination by Burst Stop command and Precharge command
- 144-pin dual in-line memory module (Pin pitch = 0.8 mm)
- Unbuffered type
- Serial PD

The information in this document is subject to change without notice.

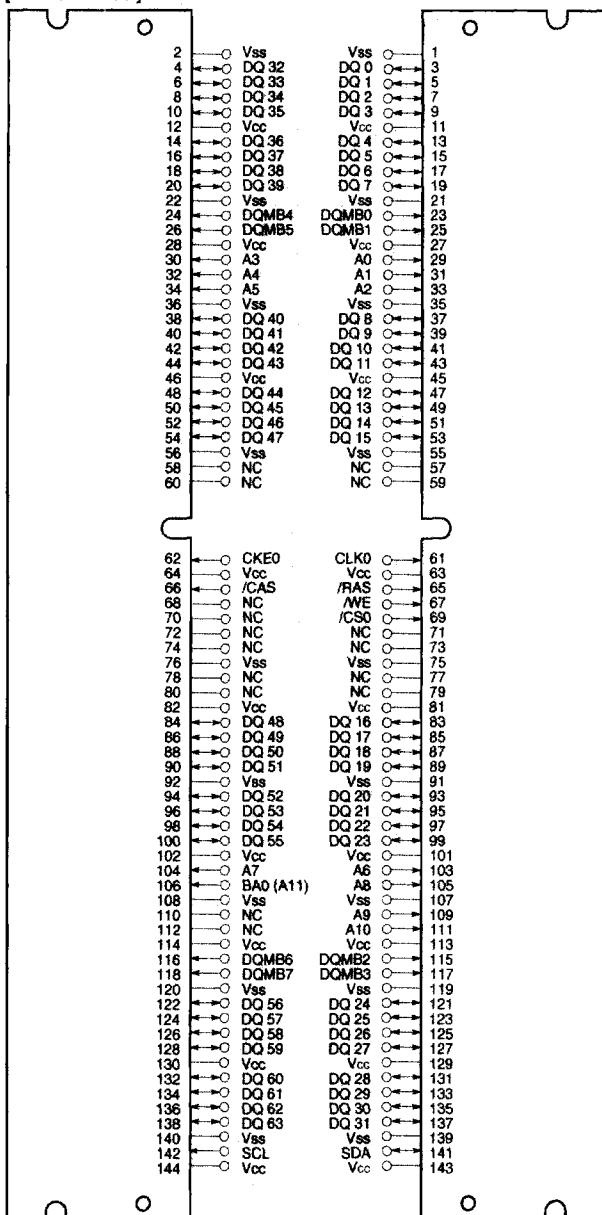
Ordering Information

Part number	Clock frequency MHz (MAX.)	Package	Mounted devices
MC-451AB64S-A10	100 MHz	144-pin Dual In-line Memory Module (Socket Type) Edge connector : Gold plated 25.4 mm (1 inch) height	4 pieces of μ PD4516161G5 (400 mil TSOP (II)) [Single side]
MC-451AB64S-A67	67 MHz		4 pieces of μ PD4516161G5-PC (400 mil TSOP (II)) SDRAM Lite [Single side]
MC-451AB64S-A12	83 MHz		4 pieces of μ PD4516161G5 (400 mil TSOP (II)) [Single side]

Pin Configuration

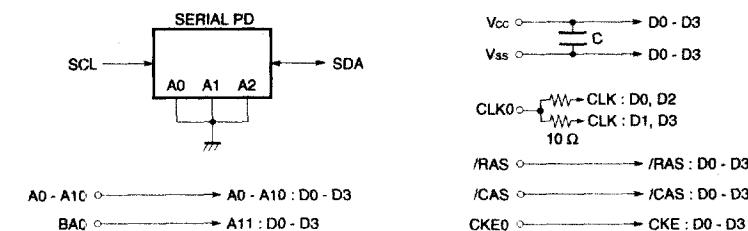
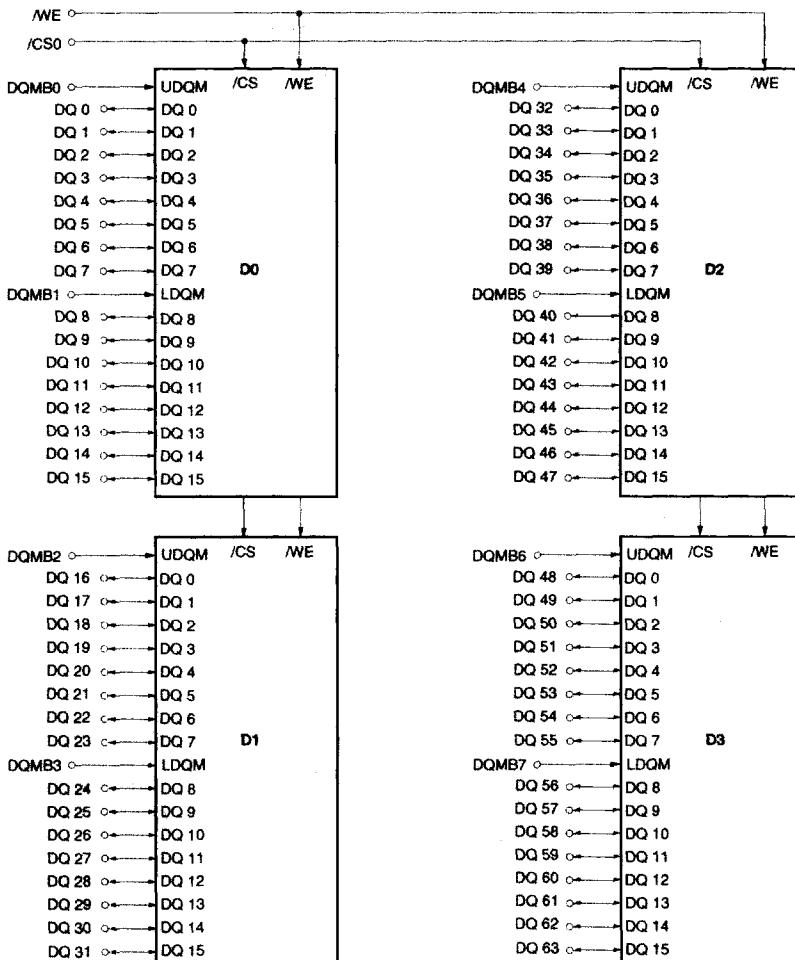
144-pin Dual In-line Memory Module Socket Type (Edge connector: Gold plated)

[MC-451AB64S]



- | | |
|------------------------------------|--------------------------|
| A0 - A10 | : Address Inputs |
| [Row: A0 - A10, Column: A0 - A7] | |
| BA0 (A11) | : SDRAM Bank Select |
| DQ0 - DQ63 | : Data Inputs/Outputs |
| CLK0 | : Clock Input |
| CKE0 | : Clock Enable Input |
| /CS0 | : Chip Select Input |
| /RAS | : Row Address Strobe |
| /CAS | : Column Address Strobe |
| /WE | : Write Enable |
| DQMB0 - DQMB7 | : DQ Mask Enable |
| SDA | : Serial Data I/O for PD |
| SCL | : Clock Input for PD |
| Vcc | : Power Supply |
| Vss | : Ground |
| NC | : No Connection |

★ Block Diagram



Remark D0 - D3 : μPD4516161(512K words x 16 bits x 2 banks)

Electrical Specifications (Preliminary)

- All voltages are referenced to Vss (GND).
- After power up, wait more than 100 μ s and then, execute power on sequence and auto refresh before proper device operation is achieved.

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Voltage on power supply pin relative to GND	V _{CC}		-1.0 to +4.6	V
Voltage on input pin relative to GND	V _I		-1.0 to +4.6	V
Short circuit output current	I _O		50	mA
Power dissipation	P _D		4	W
Operating ambient temperature	T _A		0 to +70	°C
Storage temperature	T _{SIG}		-55 to +125	°C

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	V _{CC}		3.0	3.3	3.6	V
High level input voltage	V _{IH}		2.0		4.6	V
Low level input voltage	V _{IL}		-0.3		+0.8	V
Operating ambient temperature	T _A		0		70	°C

Capacitance (T_A = 25 °C, f = 1 MHz)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C _{I1}	A0 - A10, BA0(A11), /RAS, /CAS, /WE			30	pF
	C _{I2}	CLK0			30	
	C _{I3}	CKE0			30	
	C _{I4}	/CS0			30	
	C _{I5}	DQMB0 - DQMB7			10	
Data input/output capacitance	C _{I0}	DQ0 - DQ63			10	pF

★ DC Characteristics (Recommended Operating Conditions unless otherwise noted)

Parameter	Symbol	Test condition	MIN.	MAX.	Unit	Notes	
Operating current	Icc1	Burst length = 1 tCK ≥ tCK(MIN) Io = 0 mA	/CAS latency = 2	340	mA	1	
			/CAS latency = 3	360			
Precharge standby current in power down mode	Icc2P	CKE ≤ VIL(MAX), tCK = 15 ns		12	mA		
	Icc2PS	CKE ≤ VIL(MAX), tCK = ∞		8			
Precharge standby current in non power down mode	Icc3N	CKE ≥ VH(MIN), tCK = 15 ns, /CS ≥ VH(MIN), Input signals are changed one time during 30 ns.		100	mA		
	Icc3NS	CKE ≥ VH(MIN), tCK = ∞ Input signals are stable.		24			
Active standby current in power down mode	Icc4P	CKE ≤ VIL(MAX), tCK = 15 ns		12	mA		
	Icc4PS	CKE ≤ VIL(MAX), tCK = ∞		8			
Active standby current in non power down mode	Icc5N	CKE ≥ VH(MIN), tCK = 15 ns, /CS ≥ VH(MIN), Input signals are changed one time during 30 ns.		120	mA		
	Icc5NS	CKE ≥ VH(MIN), tCK = ∞ Input signals are stable.		40			
Operating current (Burst mode)	Icc4	tCK ≥ tCK(MIN), Io = 0 mA	/CAS latency = 2	-A10	560	mA	2
				-A67	560		
				-A12	480		
			/CAS latency = 3	-A10	680		
				-A67	600		
				-A12	600		
Refresh current	Icc5	tCK ≥ tCK(MIN)			360	mA	3
Self refresh current	Icc6	CKE ≤ 0.2 V			8	mA	
Input leakage current	II(L)	V _I = 0 to 3.6 V, All other pins not under test = 0 V		-20	+20	μA	
Output leakage current	IO(L)	DO _{UT} is disabled, V _O = 0 to 3.6 V		-5	+5	μA	
High level output voltage	V _{OH}	Io = -2.0 mA		2.4		V	
Low level output voltage	V _{OL}	Io = +2.0 mA			0.4	V	

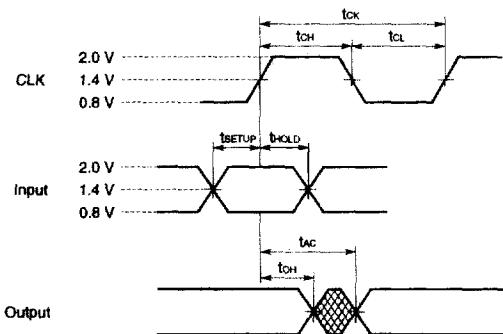
Notes 1. Icc1 depends on output loading and cycle rates. Specified values are obtained with the output open. In addition to this, Icc1 is measured on condition that addresses are changed only one time during tCK(MIN).

2. Icc4 depends on output loading and cycle rates. Specified values are obtained with the output open. In addition to this, Icc4 is measured on condition that addresses are changed only one time during tCK(MIN).

3. Icc5 is measured on condition that addresses are changed only one time during tCK(MIN).

AC Characteristics (Recommended Operating Conditions unless otherwise noted)**AC Characteristics Test Conditions**

- AC measurements assume $t_r = 1$ ns.
- Reference level for measuring timing of input signals is 1.4 V. Transition times are measured between V_{IH} and V_{IL} .
- If t_r is longer than 1 ns, reference level for measuring timing of input signals is $V_{IH(MIN)}$ and $V_{IL(MAX)}$.
- An access time is measured at 1.4 V.

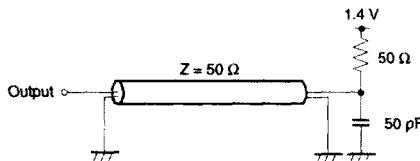


★

Synchronous Characteristics

Parameter	Symbol	-A10		-A67		-A12		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Clock cycle time	/CAS latency = 3	t _{CK3}	10		15		12		ns
	/CAS latency = 2	t _{CK2}	15		15		18		ns
Access time from CLK	/CAS latency = 3	t _{AC3}		8		9		9	ns 1
	/CAS latency = 2	t _{AC2}		10		10		12	ns 1
CLK high level width	t _{CH}	3.5		4		4		ns	
CLK low level width	t _{CL}	3.5		4		4		ns	
Data-out hold time	t _{OH}	4		3		4		ns	1
Data-out low-impedance time	t _{LZ}	0		0		0		ns	
Data-out high-impedance time	/CAS latency = 3	t _{HIZ3}	3	8	3	8	3	8	ns
	/CAS latency = 2	t _{HIZ2}	3	9	3	8	3	11	ns
Data-in setup time	t _{DS}	2.5		3		3		ns	
Data-in hold time	t _{DH}	1		1.5		1.5		ns	
Address setup time	t _{AS}	2.5		3		3		ns	
Address hold time	t _{AH}	1		1.5		1.5		ns	
CKE setup time	t _{CX3}	2.5		3		3		ns	
CKE hold time	t _{CXH}	1		1.5		1.5		ns	
CKE setup time (Power down exit)	t _{CXSP}	2.5		3		3		ns	
Command (/CS0, /RAS, /CAS, /WE, DQMB0 - DQMB7) setup time	t _{CMS}	2.5		3		3		ns	
Command (/CS0, /RAS, /CAS, /WE, DQMB0 - DQMB7) hold time	t _{CMH}	1		1.5		1.5		ns	

Note 1. Output load



★ Asynchronous Characteristics

Parameter	Symbol	-A10		-A67		-A12		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
REF to REF/ACT command period	t _{RC}	100		105		102		ns	
ACT to PRE command period	t _{RAS}	60	120,000	75	120,000	72	120,000	ns	
PRE to ACT command period	t _{RP}	30		30		30		ns	
Delay time ACT to READ/WRITE command	t _{RCD}	30		30		30		ns	
ACT(0) to ACT(1) command period	t _{RAD}	20		30		24		ns	
Data-in to PRE command period	t _{DPL}	10		15		12		ns	
Data-in to ACT(REF) command period (Auto precharge)	/CAS latency = 3	t _{DAL3}	2CLK+ 30		2CLK+ 30		2CLK+ 30		ns
	/CAS latency = 2	t _{DAL2}	1CLK+ 30		1CLK+ 30		1CLK+ 30		ns
Mode register set cycle time	t _{MSC}	20		20		20		ns	
Transition time	t _T	1	30	1	30	1	30	ns	
Refresh time	t _{REF}		32		32		32	ms	1

Note 1. 2,048 rows

★

Serial PD(1/2)

Byte No.	Function Described		Hex	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Notes
0	Defines the number of bytes written into serial PD memory		80H	1	0	0	0	0	0	0	0	128 bytes
1	Total number of bytes of serial PD memory		08H	0	0	0	0	1	0	0	0	256 bytes
2	Fundamental memory type		04H	0	0	0	0	0	1	0	0	SDRAM
3	Number of rows		05H	0	0	0	0	1	0	1	1	11 rows
4	Number of columns		06H	0	0	0	0	1	0	0	0	8 columns
5	Number of banks		01H	0	0	0	0	0	0	0	1	1 bank
6	Data width		40H	0	1	0	0	0	0	0	0	64 bits
7	Data width (continued)		00H	0	0	0	0	0	0	0	0	0
8	Voltage interface		01H	0	0	0	0	0	0	0	1	LVTTL
9	CL = 3 Cycle time	(-A10)	A0H	1	0	1	0	0	0	0	0	10 ns
		(-A67)	F0H	1	1	1	1	0	0	0	0	15 ns
		(-A12)	C0H	1	1	0	0	0	0	0	0	12 ns
10	CL = 3 Access time	(-A10)	80H	1	0	0	0	0	0	0	0	8 ns
		(-A67)	90H	1	0	0	1	0	0	0	0	9 ns
		(-A12)	90H	1	0	0	1	0	0	0	0	9 ns
11	DIMM configuration type		00H	0	0	0	0	0	0	0	0	None
12	Refresh rate/type		80H	1	0	0	0	0	0	0	0	Normal
13	SDRAM width		10H	0	0	0	1	0	0	0	0	x16
14	Error checking SDRAM width		00H	0	0	0	0	0	0	0	0	None
15	Minimum clock delay		01H	0	0	0	0	0	0	0	1	1 clock
16	Burst length supported		8FH	1	0	0	0	1	1	1	1	1, 2, 4, 8, F
17	Number of banks on each SDRAM		02H	0	0	0	0	0	0	1	0	2 banks
18	/CAS latency supported		06H	0	0	0	0	0	1	1	0	2, 3
19	/CS latency supported		01H	0	0	0	0	0	0	0	1	0
20	/WE latency supported		01H	0	0	0	0	0	0	0	1	0
21	SDRAM module attributes		00H	0	0	0	0	0	0	0	0	
22	SDRAM device attributes : General		0EH	0	0	0	0	1	1	1	0	
23	CL = 2 Cycle time	(-A10)	F0H	1	1	1	1	0	0	0	0	15 ns
		(-A67)	F0H	1	1	1	1	0	0	0	0	15 ns
		(-A12)	30H	0	0	1	1	0	0	0	0	18 ns
24	CL = 2 Access time	(-A10)	A0H	1	0	1	0	0	0	0	0	10 ns
		(-A67)	A0H	1	0	1	0	0	0	0	0	10 ns
		(-A12)	C0H	1	1	0	0	0	0	0	0	12 ns
25-26			00H	0	0	0	0	0	0	0	0	
27	tRP(MIN.)	(-A10)	1EH	0	0	0	1	1	1	1	0	30 ns
		(-A67)	1EH	0	0	0	1	1	1	1	0	30 ns
		(-A12)	1EH	0	0	0	1	1	1	1	0	30 ns
28	tRD(MIN.)	(-A10)	14H	0	0	0	1	0	1	0	0	20 ns
		(-A67)	1EH	0	0	0	1	1	1	1	0	30 ns
		(-A12)	18H	0	0	0	1	1	0	0	0	24 ns
29	tRCD(MIN.)	(-A10)	1EH	0	0	0	1	1	1	1	0	30 ns
		(-A67)	1EH	0	0	0	1	1	1	1	0	30 ns
		(-A12)	1EH	0	0	0	1	1	1	1	0	30 ns
30	tRAS(MIN.)	(-A10)	3CH	0	0	1	1	1	1	0	0	60 ns
		(-A67)	4BH	0	1	0	0	1	0	1	1	75 ns
		(-A12)	48H	0	1	0	0	1	0	0	0	72 ns
31	Module bank density		02H	0	0	0	0	0	0	1	0	8M bytes

★ Serial PD(2/2)

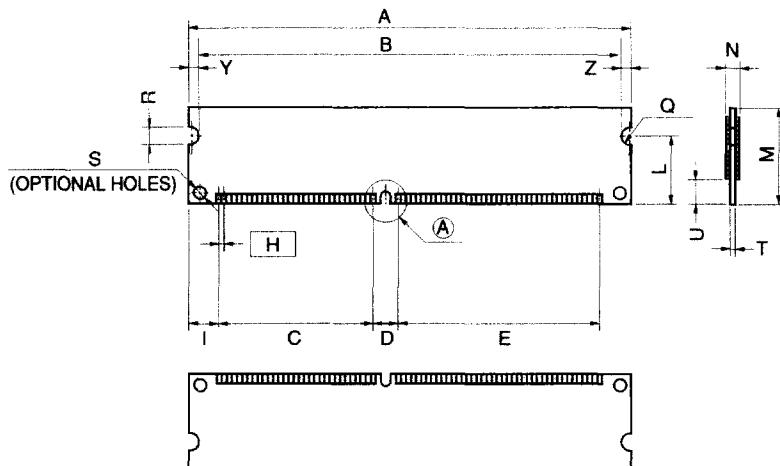
Byte No.	Function Described	Hex	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Notes
32-61		00H	0	0	0	0	0	0	0	0	
62	SPD revision	01H	0	0	0	0	0	0	0	1	1
63	Checksum for bytes 0 - 62	(-A10)	58H	0	1	0	1	1	0	0	0
		(-A67)	D1H	1	1	0	1	0	0	0	1
		(-A12)	F8H	1	1	1	1	1	0	0	0
64-71	Manufacturer's JEDEC ID code										
72	Manufacturing location										
73-90	Manufacturer's P/N										
91-92	Revision code										
93-94	Manufacturing date										
95-98	Assembly serial number										
99-126	Mfg specific										
126	Intel specification frequency	66H	0	1	1	0	0	1	1	0	66 MHz
127	Intel specification /CAS latency support	06H	0	0	0	0	0	1	1	0	2,3

Timing Chart

Please refer to the attached timing chart 1 (p.411).

Package Drawing

144 PIN SMALL OUTLINE DUAL IN-LINE MODULE (SOCKET TYPE)



ITEM	MILLIMETERS
A	67.45 - 67.75
B	63.6
C	23.2 ± 0.05
D	4.6 ± 0.05
E	32.8 ± 0.05
H	0.6 (T.P.)
I	3.3
L	20.0
M	25.4 ± 0.15
N	3.8 (MAX.)
O	R2
P	4.0 ± 0.1
Q	1.8
R	0.9 - 1.1
S	3.2
U	0.25 (MAX.)
V	0.6 ± 0.05
W	2.55 (MIN.)
X	2.0 (MIN.)
Y	2.0 (MIN.)
Z	2.0 (MIN.)